

Abstract:

The invention relates to: A chamber (101, 201, 301, 401) for processing electronic devices (414), the use of such a chamber and a method. The object of the present invention is to provide a flexible system for and method of decreasing the processing time per unit of electronic devices during production and test, thus reducing costs. The problem is solved in that the chamber (101, 201, 301, 401) is adapted for handling several devices (414) simultaneously and said processing comprises a transfer of airborne signals (429, 430, 431). This has the advantage of allowing a simultaneous test under controlled and homogeneous conditions. The invention may be used in the production and test of electronic devices such as mobile communications devices.

(Fig. 4 should be published)